



4/13/2009

**RELIABILITY MONITOR REPORT
FOR**

SVL 1.2 μ m Silicon Gate CMOS

MAXIM Integrated Products

**120 San Gabriel Dr.
Sunnyvale, CA 94086**

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX1082AEUE	MAX1082AEUE	MAX1082AEUE
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The calculated failure rate for devices using this process is:

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2007 and 9/30/2008 .

Process Information:

Process Description: SVL 1.2µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0601	MAX1082AEUE	135C	1000 HRS	80	0	N4DCBA012I#
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0649	MAX1082AEUE+	150C	1000 HRS	45	0	S4DCCQ001F#
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	0649	MAX1082AEUE+	-65C TO 150C	1000 CYS	78	0	S4DCCQ001F#
Total:						0	

TEMPERATURE HUMIDITY BIAS

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
BIASED MOISTURE	0601	MAX1082AEUE	130C, 85% R.H.	96 HRS	33	0	N4DCBA012I#
BIASED MOISTURE	0649	MAX1082AEUE+	130C, 85% R.H.	96 HRS	33	0	S4DCCQ001F#
Total:						0	

UNBIASED MOISTURE RESISTANCE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
MOISTURE SOAK	0601	MAX1082AEUE	130C, 85% R.H.	100 HRS	80	0	N4DBA012I#
MOISTURE SOAK	0649	MAX1082AEUE+	130C, 85% R.H.	96 HRS	80	0	S4DCCQ001F#
Total:						0	

